# EIA/JEDEC STANDARD

## STUB SERIES TERMINATED LOGIC FOR 2.5 VOLTS (SSTL\_2)

### EIA/JESD8-9

**SEPTEMBER 1998** 

ELECTRONIC INDUSTRIES ALLIANCE JEDEC Solid State Technology Division





#### NOTICE

EIA/JEDEC standards and publications contain material that has been prepared, reviewed, and approved through the JEDEC Council level and subsequently reviewed and approved by the EIA General Counsel.

EIA/JEDEC standards and publications are designed to serve the public interest through eliminating misunderstandings between manufacturers and purchasers, facilitating interchangeability and improvement of products, and assisting the purchaser in selecting and obtaining with minimum delay the proper product for use by those other than JEDEC members, whether the standard is to be used either domestically or internationally.

EIA/JEDEC standards and publications are adopted without regard to whether or not their adoption may involve patents or articles, materials, or processes. By such action JEDEC does not assume any liability to any patent owner, nor does it assume any obligation whatever to parties adopting the JEDEC standards or publications.

The information included in EIA/JEDEC standards and publications represents a sound approach to product specification and application, principally from the solid state device manufacturer viewpoint. Within the JEDEC organization there are procedures whereby a EIA/JEDEC standard or publication may be further processed and ultimately become an ANSI/EIA standard.

No claims to be in conformance with this standard may be made unless all requirements stated in the standard are met.

Inquiries, comments, and suggestions relative to the content of this EIA/JEDEC standard or publication should be addressed to JEDEC Solid State Technology Division, 2500 Wilson Boulevard, Arlington, VA 22201-3834, (703)907-7560/7559 or www.jedec.org.

Published by ©ELECTRONIC INDUSTRIES ALLIANCE 1998 Engineering Department 2500 Wilson Boulevard Arlington, VA 22201-3834

"Copyright" does not apply to JEDEC member companies as they are free to duplicate this document in accordance with the latest revision of JEDEC Publication 21 "Manual of Organization and Procedure".

PRICE: Please refer to the current Catalog of JEDEC Engineering Standards and Publications or call Global Engineering Documents, USA and Canada (1-800-854-7179), International (303-397-7956)

Printed in the U.S.A.

All rights reserved

#### PLEASE!

#### DON"T VIOLATE THE LAW!

This document is copyrighted by the EIA and may not be reproduced without permission.

Organizations may obtain permission to reproduce a limited number of copies through entering into a license agreement. For information, contact:

Global Engineering Documents 15 Inverness Way East Englewood, CO 80112-5704 or call U.S.A. and Canada 1-800-854-7179, International (303) 397-7956

#### STUB SERIES TERMINATED LOGIC FOR 2.5 VOLTS (SSTL\_2)

#### A 2.5V Supply Voltage Based Interface Standard for Digital Integrated Circuits

CONTENTS

	Page
1 Scope	1
1.1 Standard Structure	1
1.2 Rationale and assumptions	1
2 Supply voltage	2
2.1 Supply voltage levels	3
2.2 Input parametric	3
2.3 AC test conditions	4
<b>3</b> SSTL_2 output buffers	5
3.1 Overview	5
3.2 SSTL_2 Class I output buffers	7
3.2.1 Push-pull output buffer for symmetrically single parallel terminated loads with series resistor (VTT=0.5xVDDO).	7
3.2.2 SSTL_2 Class I output ac test conditions	8
3.3 SSTL_2 Class II output buffers	9
3.3.1 Push-pull output buffer for symmetrically double parallel terminated loads with series resistor (VTT=0.5xVDDO).	9
3.3.2 SSTL_2 Class II output ac test conditions	10
4 Other applications	10
4.1 Push-pull output buffer for unterminated loads	10
4.2 Push-pull output buffer for symmetrically single parallel terminated loads (VTT=0.5xVDDO)	11
4.3 Push-pull output buffer for externally source series terminated loads	12
4.4 Push-pull output buffer for symmetrically double parallel terminated loads	13
(VTT=0.5xVDDQ).	
Figures	
1 SSTL_2 Input voltage levels	2
2 AC Input test signal wave form	4
3 Typical output buffer (driver) environment	5
4 Example of SSTL_2, Class I, symmetrically single parallel terminated output load,	7
and series resistor	
5 Example of SSTL_2, Class II, symmetrically double parallel terminated output load	9

with series resistor

#### STUB SERIES TERMINATED LOGIC FOR 2.5 VOLTS (SSTL\_2)

### A 2.5V Supply Voltage Based Interface Standard for Digital Integrated Circuits

#### **CONTENTS** (concluded)

#### Page

<ul><li>6 Example of SSTL_2 unterminated output load</li><li>7 Example of SSTL_2, Class I or Class II, buffer with symmetrically single parallel</li></ul>	11 11
terminated output loads	
8 Example of SSTL_2, Class I or Class II, Externally Source Series terminated output	12
load	
9 Example of SSTL_2, Class I, buffer with symmetrically double parallel terminated output load	13
Tables	

#### Tables

1 Supply voltage levels	3
2a Input dc logic levels	3
2b Input ac logic levels	3
3 AC input test conditions	4
4 Examples of how the limits of SSTL_2 circuit voltages depending on VDDQ	6
5a Output dc current drives	7
5b AC test conditions	8
6 Output dc current drive	9
7 AC test conditions	10

#### STUB SERIES TERMINATED LOGIC FOR 2.5 VOLTS (SSTL\_2)

#### A 2.5V Supply Voltage Based Interface Standard for Digital Integrated Circuits

(From JEDEC Council ballot JCB-97-80, formulated under the cognizance of the JC-16 Committee on Electrical Interface and power Supply Standards for Electronic Components.)

1 Scope
---------

This standard defines the input, output specifications and ac test conditions for devices that are designed to operate in the SSTL\_2 logic switching range, nominally 0V to 2.5V. The standard may be applied to ICs operating with separate VDD and VDDQ supply voltages. In many cases VDD and VDDQ will have the same voltage level. The VDD value is not specified in this standard other than that VDDQ value may not exceed that of VDD.

#### 1.1 Standard structure

The standard is defined in three clauses:

The first clause defines pertinent supply voltage requirements common to all compliant ICs.

The second clause defines the minimum dc and ac input parametric requirements and ac test conditions for inputs on compliant devices.

The third clause specifies the minimum required output characteristics of, and ac test conditions for, compliant outputs targeted for various application environments. The output specifications are divided into two classes, Class I and Class II, which are distinguished by drive requirements and application.

A given IC need not be equipped with both classes of output drivers, but each must support at least one to claim SSTL\_2 output compliance.

The full input reference level (VREF) range specified is required on each IC in order to allow any SSTL\_2 IC to receive signals from any SSTL\_2 output driver.

#### **1.2 Rationale and assumptions**

The SSTL\_2 standard has been developed particularly with the objective of providing a relatively simple upgrade path from MOS push-pull interface designs. The standard is particularly intended to improve operation in situations where busses must be isolated from relatively large stubs. External resistors provide this isolation and also reduce the on-chip power dissipation of the drivers. Busses may be terminated by resistors to an external termination voltage.

#### 1 Scope (cont'd)

#### **1.2** Rationale and assumptions (cont'd)

Actual selection of the resistor values is a system design decision and beyond the scope of this standard. However in order to provide a basis, the driver characteristics will be derived in terms of a typical 50 Ohms environment.

While driver characteristics are derived from a 50 Ohm environment, this standard will work for other impedance levels. The system designer will be able to vary impedance levels, termination resistors and supply voltage and be able to calculate the effect on system voltage margins. This is accomplished precisely because drivers and receivers are specified independently of each other. The standard defines a reference voltage VREF which is used at the receivers as well as a voltage VTT to which termination resistors are connected. In typical applications VTT tracks as a ratio of VDDQ. In turn VREF will be given the value of VTT. In some standards this ratio equals 0.5.

#### 2 Supply voltage and logic input levels

The standard defines both ac and dc input signal values. Making this distinction is important for the design of high gain, differential, receivers that are required. The ac values are chosen to indicate the levels at which the receiver must meet its timing specifications. The dc values are chosen such that the final logic state is unambiguously defined, that is once the receiver input has crossed this value, the receiver will change to and maintain the new logic state. The reason for this approach is that many input wave-forms will include a certain amount of "ringing". The system designer can be sure that the device will switch state a certain amount of time after the input has crossed ac threshold and not switch back as long as the input stays beyond the dc threshold. The relationship of the different levels is shown in figure 1. An example of ringing is illustrated in the dotted wave-form.



Figure 1 — SSTL\_2 Input voltage levels

#### 2 Supply voltage and logic input levels (cont'd)

#### 2.1 Supply voltage levels

Symbol	Parameter	Min.	Nom	Max.	Units	Notes	
VDD	Device supply voltage	VDDQ		n/a	V	1	
VDDQ	Output supply voltage	2.3	2.5	2.7	V	1	
VREF	Input reference voltage	1.15	1.25	1.35	V	2, 3	
VTT	Termination voltage	VREF -	VREF	VREF +	V	4	
		0.04		0.04			

#### Table 1 — Supply voltage levels

#### NOTES

1 There is no specific device VDD supply voltage requirement for SSTL\_2 compliance. However under all conditions VDDQ must be less than or equal to VDD.

2 The value of VREF may be selected by the user to provide optimum noise margin in the system. Typically the value of VREF is expected to be about 0.5 x VDDQ of the transmitting device and VREF is expected to track variations in VDDQ.

- 3 Peak to peak ac noise on VREF may not exceed +/-2% VREF (dc).
- 4 VTT of transmitting device must track VREF of receiving device.

#### 2.2 Input parametric

Symbol	Parameter	Min.	Max.	Units	Notes		
VIH (dc)	dc input logic high	VREF + 0.18	VDDQ + 0.3	V	1		
VIL (dc)	dc input logic low	- 0.3	VREF - 0.18	V	1		

Table 2a — Input dc logic levels

NOTE 1 — Within this standard, it is the relationship of the VDDQ of the driving device and the VREF of the receiving device that determines noise margins. However, in the case of VIH (Max.) (i.e. input overdrive) it is the VDD of the receiving device that is referenced. In the case where a device is implemented that supports SSTL\_2 inputs but has no SSTL\_2 outputs (e.g., a translator), and therefore no VDDQ supply voltage connection, inputs must tolerate input overdrive to 3.0 V (High corner VDDQ + 300 mV).

Symbol	Parameter	Min.	Max.	Units	Notes
VIH (ac)	ac input logic high	VREF + 0.35		V	
VIL (ac)	ac input logic low		VREF - 0.35	V	

#### Table 2b — Input ac logic levels

#### 2 Supply voltage and logic input levels (cont'd)

#### 2.3 AC Test Conditions

The ac input test conditions are specified to be able to obtain reliable, reproducible test results in an automated test environment, where a relatively high noise environment makes it difficult to create clean signals with limited swing. The tester may therefore supply signals with a 1.5 V peak to peak swing to drive the receiving device. Note however, that all timing specifications are still set relative to the ac input level. This is illustrated in figure 2.

Symbol	Condition	Value	Units	Notes
VREF	Input reference voltage	0.5 x VDDQ	V	1,4
VSWING max	Input signal maximum peak to peak swing	1.5	V	1,2
SLEW	Input signal minimum slew rate	1.0	V/ns	3

#### NOTES

1 In all cases, input wave-form timing is referenced to the input signal crossing through the VREF level applied to the device under test. Table 1 identifies the VREF range supported in SSTL\_2.

2 Compliant devices must still meet the VIH(ac) and VIL(ac) specifications under actual use conditions.

3 The 1V/ns input signal minimum slew rate is to be maintained in the VILmax (ac) to VIHmin (ac) range of the input signal swing, consistent with the ac logic specification of table 2b. See also figure 2.

4 AC test conditions may be measured under nominal voltage conditions as long as the supplier can demonstrate by analysis that the device will meet its timing specifications under all supported voltage conditions.



Figure 2 — AC Input Test Signal Wave Form

#### **3** SSTL\_2 Output Buffers

#### 3.1 Overview

This specification sets minimum requirements for output buffers in such a way that when they are applied within the range of power supply voltages specified in SSTL\_2 and are used in conjunction with SSTL\_2 input receivers then the input receiver specifications can be met or exceeded. The specifications are quite different from traditional specifications, where minimum values for VOH and maximum values for VOL are set which apply to the entire supply range. In SSTL\_2, the input voltage provided to the receiver depends on the driver as well as on the termination voltage and termination resistors. Figure 3 shows the typical dc environment that the output buffer is presented with.



Figure 3 — Typical Output Buffer (Driver) environment

Of particular interest here are the values VOUT and VIN. These values depend not only on the current drive capabilities of the buffer, but also on the values of VDDQ and VTT (VREF is equal to VTT). The important condition is that VIN be at least 380mV above or below VREF as a result of VOUT attaining its maximum low or it's minimum high value. As will be seen later, the two cases of interest for SSTL\_2 are where the series resistor RS equals 25 Ohms and the termination resistor RT equals 50 Ohms (for Class I) or 25 Ohms (for Class II). VTT is specified as being equal to 0.5 x VDDQ.

In order to meet the 380mV minimum requirement for Vin, a minimum of 7.6mA must be developed across RT if RT equals 50 Ohms (Class I) or 15.2mA in case RT equals 25 Ohms (Class II). The driver specification now must guarantee that these values of VIN are obtained in the worst case conditions specified by this standard.

#### 3 SSTL\_2 Output Buffers (cont'd)

#### 3.1 Overview (cont'd)

(For reference only)									
Condition	Units	Class I	Class I	Class I	Class II	Class II	Class II		
VDDQ	V	2.3	2.5	2.7	2.3	2.5	2.7		
VTTmin	V	1.11	1.25	1.31	1.11	1.25	1.31		
VTTmax	V	1.19	1.25	1.39	1.19	1.25	1.39		
VREF	V	1.15	1.25	1.35	1.15	1.25	1.35		
RT	Ohm	50	50	50	25	25	25		
RS	Ohm	25	25	25	25	25	25		
Delta VIN	V	0.35	0.35	0.35	0.35	0.35	0.35		
Delta VOUT1	V	0.38	0.38	0.38	0.38	0.38	0.38		
Delta VOUT2	V	0.57	0.57	0.57	0.76	0.76	0.76		
Output High Drive									
Minimum Voltage at VIN	V	1.57	1.63	1.77	1.57	1.63	1.77		
Minimum Voltage at	V	1.76	1.82	1.96	1.95	2.01	2.15		
VOUT									
Minimum Output Current	mA	-7.6	-7.6	-7.6	-15.2	-15.2	-15.2		
Maximum On Resistance	Ohm	71.1	89.5	97.4	23.0	32.2	36.2		
Output Low Drive	]								
Maximum Voltage at VIN	V	0.73	0.87	0.93	0.73	0.87	0.93		
Maximum Voltage at	V	0.54	0.68	0.74	0.35	0.49	0.55		
VOUT									
Minimum Output Current	mA	7.6	7.6	7.6	15.2	15.2	15.2		
Maximum On Resistance	Ohm	71.1	89.5	97.4	23.0	32.2	36.2		

Table 4 — Spread sheet showing how the limits of SSTL_2 circuit	voltages depending on VDDQ.
(For reference only)	

Delta VOUT1 (dVOUT1) is voltage across RT in figure 3

Delta VOUT2 (dVOUT2) is total voltage across RS and RT in figure 3

These values follow from an analysis of figure 3 with fixed driver current. Thus, for output low voltage, VIN=VTT - I x RT; VOUT=VTT - I x (RT+RS); On Resistance = VTT/I - (RT+RS).

As can be seen from table 4 the most stringent requirements will result where VDDQ = 2.3 V, since for that case the output driver transistors must have the lowest "on" resistance. If the driver outputs are sized for this condition, then for all other VDDQ voltage applications, the resulting input signal

will be larger than the minimum required 380mV.

### 3.2 SSTL\_2 Class I output buffers

**3.2.1** Push-pull output buffer for symmetrically single parallel terminated loads with series resistor. (VTT=0.5xVDDQ)

Symbol	Parameter	Min.	Max.	Units	Notes
IOH (dc)	Output minimum source dc current	-7.6		mA	1,3,4
IOL (dc)	Output minimum sink dc current	7.6		mA	2,3,4

 Table 5a — Output dc current drives

NOTES

1 VDDQ = 2.3 V; VOUT = VDDQ - 0.62 V

2 VDDQ = 2.3 V; VOUT = 0.54V.

3 The dc value of VREF applied to the receiving device is expected to be set to VTT.

4 The values of IOH(dc) and IOL(dc) are based on VDDQ = 2.3V and VTT = 1.11V. They are used to test device current drive capability which ultimately delivers acceptable noise margin for an SSTL\_2 receiver. Under these conditions VOH is 1.68V and VOL is 0.54V. Under other conditions for VDDQ and VTT the typical output levels are discussed in 3.1 (Overview).



Figure 4 — Example of SSTL\_2, Class I, symmetrically single parallel terminated output load, and series resistor

#### 3.2 SSTL\_2 Class I output buffers (cont'd)

#### 3.2.2 SSTL\_2 Class I output ac test conditions

This testing regimen is used to verify SSTL\_2 Class I type output buffers (push-pull output buffers designed for symmetrically single parallel terminated loads with series resistor).

This clause is added to set the conditions under which the driver ac specifications can be tested. The test circuit is assumed to be similar to the circuit shown in figure 4. AC test conditions may be measured under nominal voltage conditions as long as the supplier can demonstrate by analysis, that the device will meet its timing specifications under all supported voltage conditions. Table 5a assumes that +/-0.38V must be developed across the 50 Ohm termination resistor at VIN. With a series resistor of 25 Ohms this translates into a minimum requirement of 0.57 Volt swing relative to VTT , at the output of the device.

Symbol	Condition	Value	Units	Notes
VOH	Minimum required output pull-up under ac test	VTT + 0.57	V	
	load			
VOL	Maximum required output pull-down under ac	VTT - 0.57	V	
	test load			
VOTR	Output timing measurement reference level	0.5 x	V	1
		VDDQ		

Table 5b — ac test conditions

NOTE 1 — The VDDQ of the device under test is referenced.

#### 3.3 SSTL\_2 Class II output buffers

**3.3.1** Push-pull output buffer for symmetrically double parallel terminated loads with series resistor (VTT = 0.5 x VDDQ)

Symbol	Parameter	Min.	Max.	Units	Notes
IOH (dc)	Output minimum source dc current	-15.2		mA	1,3,4
IOL (dc)	Output minimum sink dc current	15.2		mA	2,3,4

 Table 6 — Output dc current drive

NOTES

1 VDDQ = 2.3 V; VOUT = VDDQ - 0. 43V

2 VDDQ = 2.3 V; VOUT = 0.35V.

3 The dc value of VREF applied to the receiving device is expected to be set to VTT.

4 The values of IOH(dc) and VOL(dc) are based on VDDQ = 2.3V and VTT = 1.11V. They are used to test device current drive capability which ultimately delivers acceptable noise margin for an SSTL\_2 receiver. Under these conditions VOH is 1.87V and VOL is 0.35V. Under other conditions for VDDQ and VTT the typical output levels are discussed in 3.1 (Overview).



Figure 5 — Example of SSTL\_2, Class II, symmetrically double parallel terminated output load with series resistor

#### 3.3 SSTL\_2 Class II output buffers (cont'd)

#### 3.3.2 SSTL\_2 Class II output ac test conditions

This testing regimen is used to verify SSTL\_2 Class II type output buffers (push-pull output buffers designed for symmetrically double parallel terminated loads with series resistor).

This clause is added to set the conditions under which the driver ac specifications can be tested. The test circuit is assumed to be similar to the circuit shown in figure 5. AC test conditions may be measured under nominal voltage conditions as long as the supplier can demonstrate by analysis, that the device will meet its timing specifications under all supported voltage conditions. Table 7 assumes that  $\pm 0.38V$  must be developed across the effectively 25 Ohm termination resistor at VIN . With a series resistor of 25 Ohms this translates into a minimum requirement of 0.76Volt swing relative to VTT, at the output of the device.

Symbol	Condition	Value	Units	Notes
VOH	Minimum required output pull-up under ac test load	VTT + 0.76	V	
VOL	Maximum required output pull-down under ac test	VTT - 0.76	V	
	load			
VOTR	Output timing measurement reference level	0.5xVDDQ	V	1

Table 7 –	– ac test	conditions
-----------	-----------	------------

NOTE 1 — The VDDQ of the device under test is referenced.

#### **4** Other Application (For reference only)

The specifications for Class I and II were based on an environment comprising both series and parallel terminating resistors. In this non binding section we will show some derived applications. Clearly it is not the intention to show all possible variations in this standard.

#### 4.1 Push-pull output buffer for unterminated loads

In many applications where interconnections are short, there is no need for any termination at all. An example of this is shown in figure 6. This application can be served by a Class I or Class II type buffer and an SSTL\_2 type receiver.

#### 4 Other Application (For reference only) (cont'd)



4.1 Push-pull output buffer for unterminated loads (cont'd)

Figure 6 — Example of SSTL\_2 unterminated output load

#### **4.2** Push-pull output buffer for symmetrically single parallel terminated loads (VTT = .5xVDDQ)

Sometimes the system application requires longer transmission lines that will only be terminated at one end. An example of this may be address drivers on a memory board. This application can also be served with a Class I or Class II type buffer and an SSTL\_2 receiver. An example is shown in figure 7.



Figure 7 — Example of SSTL 2, Class I or Class II, buffer with symmetrically single parallel terminated output loads.

#### 4 Other Application (For reference only) (cont'd)

#### 4.3 Push-pull output buffer for externally source series terminated loads

In other applications the system designer may wish to terminate at the signal source rather than at the end of the transmission line. One advantage of this approach is that there is no need for a VTT power supply. This application may again be served with a Class I or Class II type buffer and SSTL\_2 receiver. An example is shown in figure 8. In this example a Class II type buffer might be preferred since it comes closer, in conjunction with the series resistor, to match the characteristic impedance of the transmission line.



Figure 8 — Example of SSTL\_2, Class I or Class II, Externally Source Series terminated output load

#### 4 Other Application (For reference only) (cont'd)

### **4.4** Push-pull output buffer for symmetrically double parallel terminated loads (VTT = 0.5 x VDDQ)

Finally, the system designer may require a bus system which must be terminated at both sides. However, the drivers are connected directly onto the bus so there are no stubs present. In that case, the designer may decide to eliminate the series resistors entirely. This application can be implemented using a Class I or Class II driver and SSTL\_2 receiver. However a Class II buffer would dissipate more power due to its larger current drive and thus might require special cooling.



Figure 9 — Example of SSTL\_2, Class I, buffer with symmetrically double parallel terminated output load

JEDEC Standard No. 8-9 Page 14

